

2006 IEEE International High Level Design Validation and Test Workshop

**Monterey, CA
8-10 November 2006**



IEEE Catalog Number:

06EX1547

ISBN:

1-4244-0679-X

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IEEE Catalog Number: 06EX1547
ISBN: 1-4244-0679-X
ISSN: 1552-6674

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Table of Contents

ELEVENTH ANNUAL IEEE INTERNATIONAL HIGH-LEVEL DESIGN VALIDATION AND TEST WORKSHOP

Chairs' Welcome Message	iii
Conference Organizers	iv
Committees	iv

Session 1: Test Case Generation I

DVGen: Increasing Coverage by Automatically Combining Test Specifications	3
Kevin D. Rich, Robert Shaw, Shankar G. Govindaraju, David Dobrikin (Transmeta Corp.)	
Test Directive Generation for Functional Coverage Closure Using Inductive Logic Programming	11
Hsiou-Wen Hsueh, Kerstin Eder (Univ. of Bristol)	
Automated Coverage Directed Test Generation Using a Cell-Based Genetic Algorithm	19
Amer Samarah, Ali Habibi, Sofiene Tahar, Nawwaf Kharma (Concordia Univ.)	

Session 2: Special Session I

Disjunctive Transition Relation Decomposition for Efficient Reachability Analysis	29
Stergios Stergiou (Stanford Univ.) Jawahar Jain (Fujitsu Labs.)	
Trends in Test: Challenges and Techniques	37
Wolfgang Meyer (Synopsys, Inc.)	
Formal Verifications in Modern Chip Designs	38
Kei-Yong Khoo (Cadence Design Systems, Inc.)	

Session 3: Testing and Design for Testability

DFT and Probabilistic Testability Analysis at RTL	41
José M. Fernandes, Marcelino B. Santos, Arlindo L.Oliveira, João C. Teixeira (IST/INESC-ID)	
Easily Testable Implementation for Bit Parallel Multipliers in GF (2^m)	48
H. Rahaman, J. Mathew, D. K. Pradhan (Univ. of Bristol) A. M. Jabir (Oxford Brookes Univ.)	

Error Detection Using Model Checking vs. Simulation.....	55
Shireesh Verma, Patricia Lee, Ian G. Harris (Univ. of California, Irvine)	

Session 4: Assertions and Transactions

Assertion-based Verification of Behavioral Descriptions with Non-linear Solver	61
I. Ugarte, P. Sanchez (Univ. of Cantabria)	

Efficient Automata-Based Assertion-Checker Synthesis of PSL Properties	69
Marc Boule, Zeljko Zilic (McGill Univ.)	

Specification Language for Transaction Level Assertions.....	77
Wolfgang Ecker, Volkan Esen, Michael Hull, Thomas Steininger, Michael Velten (Infineon Technologies AG)	

On the Automatic Transactor Generation for the TLM-based Design Flows	85
Nicola Bombieri, Franco Fummi (Universita di Verona)	

Session 5: Test Case Generation II

Addressing Test Generation Challenges for Configurable Processor Verification.....	95
M. Rimon, Y. Lichtenstein, A. Adir, I. Jaeger, M. Vinov (IBM Corp.) S. Johnson, D. Jani (Tensilica, Inc.)	

DeepTrans - Extending the Model-based Approach to Functional Verification of Address Translation Mechanisms	102
Allon Adir, Laurent Fournier, Yoav Katz, Anatoly Koyfman (IBM Corp.)	

CP with Architectural State Lookup for Functional Test Generation	111
B. Gutkovich, A. Moss (Intel Corp.)	

Reusable On-Chip System Level Verification for Simulation Emulation and Silicon	119
Avishay Maman, Sharon Goldschlager, Hillel Miller, David Bell, Rob Slater, Oded Ben-Moshe, Nissan Levi, Hagit Gilboa (Freescale Semiconductor)	

Session 6: Transformation-based Verification

Transaction Routing and its Verification by Correct Model Transformations	129
Samar Abdi, Daniel Gajski (Univ. of California, Irvine)	

Taming the Complexity of STE-based Design Verification Using Program Slicing	137
Vivekananda M. Vedula, Flemming L. Andersen (Intel Corp.) Jacob A. Abraham (Univ. of Texas)	

MMV: Metamodeling Based Microprocessor Validation Environment	143
Ajit Dingankar (Intel Corp.)	
Deepak A. Mathaikutty, Sandeep Shukla (CESCA, Virginia Tech)	
Sreekumar V. Kodakara, David Lilja (Univ. of Minnesota)	

Session 7: Special Session II

Distance-Guided Hybrid Verification with GUIDO	151
Valeria Bertacco (Univ. of Michigan)	

EverLost: A Flexible Platform for Industrial-Strength Abstraction-Guided Simulation	151
Alan J. Hu (Univ. of British Columbia)	

Semi-Formal Verification at IBM.....	152
Jason Baumgartner (IBM Corp.)	

Session 8: SAT and Equivalence Verification

Guiding CNF-SAT Search by Analyzing Constraint-Variable Dependencies and Clause Lengths	155
Vijay Durairaj, Priyank Kalla (Univ. of Utah)	

Equivalence Checking with Rule-Based Equivalence Propagation and High-Level Synthesis.....	162
Tasuku Nishihara, Takeshi Matsumoto, Masahiro Fujita (Univ. of Tokyo)	

Practical Issues in Sequential Equivalence Checking through Alignability: Handling Don't Cares and Generating Debug Traces	170
In-Ho Moon, Per Bjesse, Carl Pixley (Synopsys, Inc.)	

IChecker: An Efficient Checker for Inductive Invariants.....	176
Feng Lu, K.-T. Cheng (Univ. of California, Santa Barbara)	

Session 9: Panel: Assertion-Based Verification - What is the Big Deal?	183
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Organizer: Sandeep Shukla, Virginia Tech.
Moderator: Alan Hu, Univ. of British Columbia
Panelists: Carl Pixley, Synopsys, Inc.
Harry Foster, Mentor Graphics
Pranav Ashar, Real Intent
Jacob Abrahams, Univ. of Texas

Session 10: System Level View and Modeling

Runtime Deadlock Analysis of SystemC Designs	187
Eric Cheung, Piyush Satapathy, Vi Pham, Harry Hsieh (Univ. of California, Riverside)	
Xi Chen (Novas Software, Inc.)	

Extracting a simplified view of design functionality via vector simulation.....	195
Onur Guzey, Charles Wen, Li-C. Wang (Univ. of California, Santa Barbara)	
Tao Feng (Cadence Design Systems, Inc.)	
Magdy S. Abadir (Freescale Semiconductor)	
A Tool for Automatic Detection of Deadlock in Wormhole Networks on Chip	203
Sami Taktak, Jean-Lou Desbarbieux (Univ. of Paris VI.)	
Emmanuelle Encrenaz (LVS-ENS Cachan & CNRS)	
Polychronous Methodology for System Design: A True Concurrency Approach	211
Syed Suhaib, Deepak Mathaikutty, Sandeep Shukla (Virginia Tech)	
Jean-Pierre Talpin (INRIA-IRISA)	